



FUNDAMENTALS OF ATE

As part of a comprehensive skill development curriculum, Teradyne's Test Assistance Group (TAG) provides training that focuses on helping your engineers to become proficient in using Teradyne device testing systems.

For customer engineers who want to master ATE test basics, Fundamentals of ATE will lay the groundwork for their success.

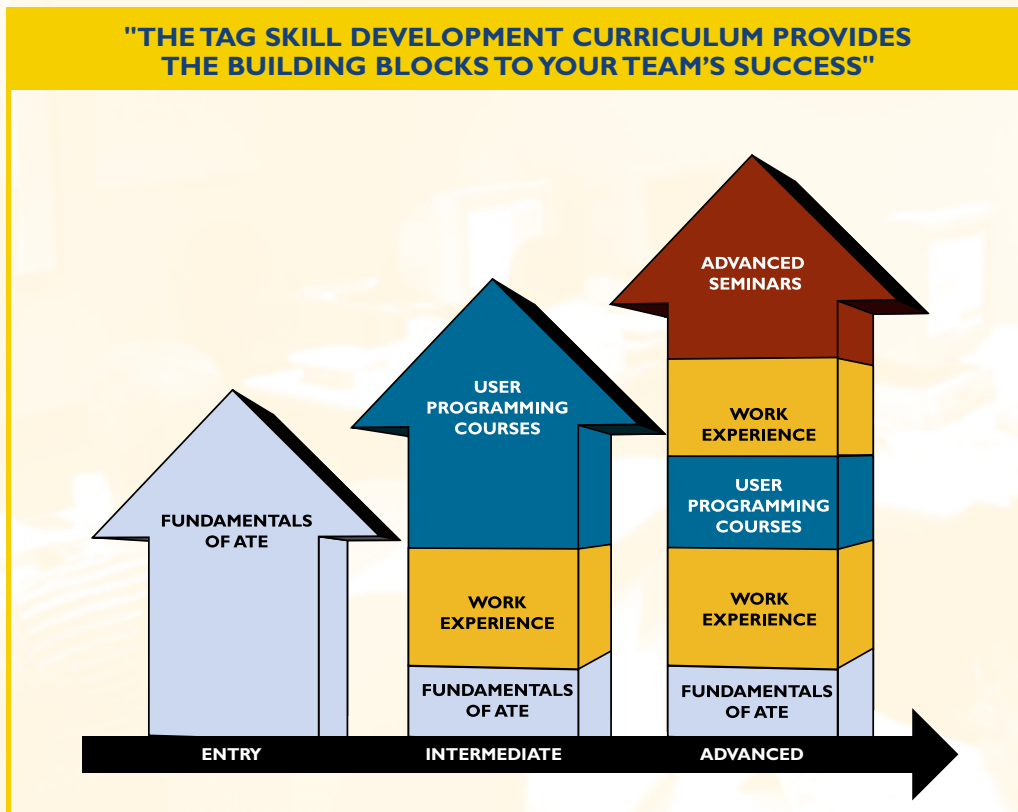
TAG offers two courses, each covering a primary area of test technology:

- Fundamentals of Digital Testing
- Fundamentals of Mixed-Signal Testing

These courses are a recommended prerequisite for Teradyne programming courses. Test development expertise is not required to participate. All of our Skill Development courses and seminars are taught by Teradyne certified instructors and will guide the student through a progressive gradient of knowledge, from general concepts to more comprehensive ATE test techniques.

COURSE OBJECTIVES

- Provide students with first-hand expertise in testing, with a focus on Teradyne systems.
- Enable a smooth transition from entry to advanced levels of Teradyne system training knowledge.



FUNDAMENTALS OF DIGITAL TESTING

- Basic electrical engineering to semiconductor ATE test concepts
- Understanding device specifications
- Open and Shorts to verification of DC and function parameters
- AC parameter verifications and device characterizations
- Test vector development and related issues
- Test program generation
- CMOS latch-up and SCAN testing

FUNDAMENTALS OF MIXED-SIGNAL TESTING

- Overview of digital testing
- Overview of mixed-signal testing
- DSP fundamentals including sampling theory and examples
- Understanding mixed-signal device specifications
- DAC static measurements and dynamic parameters
- General mixed-signal test issues

For additional information visit our web site at www.teradyne.com/tag



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